- **High Performance 1:5 PLL Clock** Synchronizer
- Two Clock Inputs: VCXO\_IN Clock Is Synchronized To REF\_IN Clock
- Synchronizes Frequencies Up To 800 MHz (VCXO\_IN)
- Supports Five Differential LVPECL Outputs
- Each Output Frequency Is Selectable By x1, /2, /4, /8, /16
- **All Outputs Are Synchronized**
- Integrated Low-Noise OPA For External Low-Pass Filter
- Efficient Jitter Screening From Low PLL Loop Bandwidth
- Low-Phase Noise Characteristic
- **Programmable Delay For Phase** Adjustments
- Predivider Loop BW Adjustment
- SPI Controllable Division Setting
- **Power-Up Control Forces LVPECL Outputs** to 3-State at VCC < 1.5 V
- 3.3-V Power Supply
- Packaged In 64-Pin BGA (0,8 mm Pitch -ZVA) or 48-Pin QFN (RGZ)
- Industrial Temperature Range –40°C To 85°C

### description

The CDC7005 is a high-performance, low-phase noise, and low-skew clock synthesizer and jitter cleaner that synchronizes the voltage controlled crystal oscillator (VCXO) frequency to the reference clock. The programmable predividers M and N give a high flexibility to the frequency ratio of the reference clock to VCXO: VCXO\_IN/ REF IN = (NxP)/M. The VCXO IN clock operates up to 800 MHz. Through the selection of external





VCXO and loop filter components, the PLL loop bandwidth and damping factor can be adjusted to meet different system requirements. Each of the five differential LVPECL outputs are programmable by the serial peripheral interface (SPI). The SPI allows individual control of frequency and enable/disable state of each output. The device operates in 3.3-V environment. The built-in latches ensure that all outputs are synchronized.

The CDC7005 is characterized for operation from -40°C to 85°C.



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#### functional block diagram





### Pin Functions

	PIN		-	DECODIDEION
NAME	BGA	QFN	TYPE	DESCRIPTION
AVCC	C3, C4, C5, C6, C7	27, 30, 32, 38, 39	Power	3.3-V analog power supply
CP_OUT	A4	31	0	Charge pump output
CTRL_LE	A1	36	I	LVCMOS input, control load enable for serial programmable interface (SPI) with hysteresis. Unused or floating inputs must be tied to proper logic level. It is recommend to use a $20k\Omega$ or larger pull–up resistor to VCC.
CTRL_CLK	A2	35	I	LVCMOS input, serial control clock input for SPI, with hysteresis. Unused or floating inputs must be tied to proper logic level. It is recommend to use a $20k\Omega$ or larger pull–up resistor to VCC.
CTRL_DATA	A3	33	I	LVCMOS input, serial control data input for SPI, with hysteresis. Unused or floating inputs must be tied to proper logic level. It is recommend to use a $20k\Omega$ or larger pull–up resistor to VCC.
GND	B2, B3, B4, B5, B6, B7, B8, C2, D2, D3, D4, D5, D6, E2, F2, F3, F4, F5, F6	Thermal pad and pin 24	Ground	Ground
I_REF	C1	40	0	Current path for external reference resistor (12 k $\Omega \pm 1\%$ ) to support an accurate charge pump current, optional. Do not use any capacitor across this resistor to prevent noise coupling via this node. If internal 12 k $\Omega$ is selected (default setting), this pin can be left open.
NC	-	34	-	Not connected
NPD	H1	1	I	LVCMOS input, asynchronous power down (PD) signal active on low. Switches all current sources off, resets all dividers to default values, and 3-states all outputs. Has an internal 150-k $\Omega$ pullup resistor. Note 2: It is recommended to ramp up NPD at the same time with VCC and AVCC or later. The ramp up rate should not be faster than the ramp up rate of VCC and AVCC
NRESET	H8	14	I	LVCMOS input, asynchronous reset signal active on low. Resets the counter of all dividers to zero keeping its divider values the same. It has an internal $150$ -k $\Omega$ pullup resistor. Yx outputs are switched low during reset.
OPA_IN	A5	29	I	Inverting input of the op amp, see Note 1
OPA_OUT	A7	26	0	Output of the op amp, see Note 1
OPA_IP	A6	28	I	Noninverting input of the op amp, see Note 1
REF_IN	B1	37	I	LVCMOS reference clock input
STATUS_LOCK	A8	25	0	This pin is high if the PLL lock definition is valid. PLL lock definition means the rising edge of REF_IN clock and VCXO_IN clock for PFD are inside the lock detect window for at least five successive input clock cycles. If the rising edge of REF_IN clock and VCXO_IN clock are out of the selected lock detect window, this pin will be low, but it does not refer to the real lock condition of the PLL. This means, that i.e. due to a strong jitter at REF_IN or VCXO_IN STATUS_LOCK can be low, even if the PLL is in Lock. The PLL is in lock for sure, if STATUS_LOCK is high.See Table 8 and Figure 4.
STATUS_REF	C8	23	0	LVCMOS output provides the status of the reference input (frequencies above 3.5 MHz are interpreted as valid clock, active high)
STATUS_VCXO	D8	22	0	LVCMOS outputs provides the status of the VCXO input (frequencies above 10 MHz are interpreted as valid clock, active high)



VCC	D7, E3, E4, E5, E6, E7, E8, F7, G2, G3, G4, G5, G6, G7	2, 5, 6, 9, 10, 13, 15, 18, 19, 20, 21, 41, 44, 45, 48	Power	3.3-V supply VCC and AVCC should have always same supply voltage
VCXO_IN	D1	42	I	VCXO LVPECL input
VCXO_INB	E1	43	I	Complementary VCXO LVPECL input
Y[0:4]	F1, H2, H4, H6, G8	46, 3, 7, 11, 16	0	LVPECL output
Y[0:4]B	G1, H3, H5, H7, F8	47, 4, 8, 12, 17	0	Complementary LVPECL output

NOTE 1: If the internal operational amplifier is not used, these pins can be left open.

#### **SPI control interface**

The serial interface of the CDC7005 is a simple SPI-compatible interface for writing to the registers of the device. It consists of three control lines: CTRL\_CLK, CTRL\_DATA, and CTRL\_LE. There are four 32-bit wide registers, which can be addressed by the two LSBs of a transferred word (bit 0 and bit 1). Every transmitted word must have 32 bits, starting with MSB first. Each word can be written separately. It is recommended to program Word 0, Word 1, Word 2 and Word 3 right after power up and NPD becomes HIGH. The transfer is initiated with the falling edge of CTRL\_LE; as long as CTRL\_LE is high, no data can be transferred. During CTRL\_LE, low data can be written. The data has to be applied at CTRL\_DATA and has to be stable before the rising edge of CTRL\_CLK. The transmission is finished by a rising edge of CTRL\_LE. With the rising edge of CTRL\_LE, the new word is asynchronously transferred to the internal register (e.g., N, M, P, ...). Each word has to be separately transmitted by this procedure. Unused or floating inputs must be tied to proper logic level. It is recommend to use a  $20k\Omega$  or larger pull–up resistor to VCC.



Figure 1. Timing Diagram SPI Control Interface



BIT	BIT NAME		DESCRIPTION / FUNCTION	TYPE	POWER-UP CONDITION	PIN AFFECTED
0	C0		Register selection	W	0	
1	C1		Register selection	W	0	
2	MO		Reference divider M bit 0	W	1	
3	M1		Reference divider M bit 1	W	1	
4	M2		Reference divider M bit 2	W	1	
5	M3		Reference divider M bit 3	W	1	
6	M4		Reference divider M bit 4	W	1	
7	M5	Reference Divider M	Reference divider M bit 5	W	1	
8	M6		Reference divider M bit 6	W	1	
9	M7		Reference divider M bit 7	W	0	
10	M8		Reference divider M bit 8	W	0	
11	M9		Reference divider M bit 9	W	0	
12	MD0		Reference delay M bit 0	W	0	
13	MD1	Reference Delay M	Reference delay M bit 1	W	0	
14	MD2		Reference delay M bit 2	W	0	
15	PFD0		PFD pulse width PFD bit 0	W	0	A4
16	PFD1	PFD Pulse Width	PFD pulse width PFD bit 1	W	0	A4
17	PFD2		PFD pulse width PFD bit 2	W	0	A4
18	CP0		CP current setting bit 0	W	1	A4
19	CP1	05.0	CP current setting bit 1	W	0	A4
20	CP2	CP Current	CP current setting bit 2	W	0	A4
21	CP3		CP current setting bit 3	W	1	A4
22	Y03St		Y0 3-state (1 = output enabled)	W	1	F1, G1
23	Y13St		Y1 3-state (1 = output enabled)	W	1	H2, H3
24	Y23St		Y2 3-state (1 = output enabled)	W	1	H4, H5
25	Y33St	Output 3-State	Y3 3-state (1 = output enabled)	W	1	H6, H7
26	Y43St		Y4 3-state (1 = output enabled)	W	1	G8, F8
27	CP3St		CP 3-state (1 = output enabled)	W	1	A4
28	OP3St		OPA 3-state and disable (1 = OPA enabled)	W	0	A7
29	MUXS0		MUXSEL select bit 0	W	1	
30	MUXS1	MUXSEL	MUXSEL select bit 1	W	1	
31	MUXS2		MUXSEL select bit 2	W	0	

#### Table 1. Word 0



BIT	BIT NAME		DESCRIPTION / FUNCTION	TYPE	POWER-UP CONDITION	PIN AFFECTED
0	C0		Register selection	W	1	
1	C1		Register selection	W	0	
2	N0		VCXO divider N bit 0	W	1	
3	N1		VCXO divider N bit 1	W	1	
4	N2		VCXO divider N bit 2	W	1	
5	N3		VCXO divider N bit 3	W	1	
6	N4	VCXO	VCXO divider N bit 4	W	1	
7	N5	Divider N <sup>†</sup>	VCXO divider N bit 5	W	1	
8	N6		VCXO divider N bit 6	W	1	
9	N7		VCXO divider N bit 7	W	0	
10	N8		VCXO divider N bit 8	W	0	
11	N9		VCXO divider N bit 9	W	0	
12	ND0		VCXO delay N bit 0	W	0	
13	ND1	VCXO Delay N	VCXO delay N bit 1	W	0	
14	ND2	Delay N	VCXO delay N bit 2	W	0	
15	MUX00		MUX0 select bit 0	W	0	F1, G1
16	MUX01	MUX0	MUX0 select bit 1	W	0	F1, G1
17	MUX02		MUX0 select bit 2	W	0	F1, G1
18	MUX10		MUX1 select bit 0	W	1	H2, H3
19	MUX11	MUX1	MUX1 select bit 1	W	0	H2, H3
20	MUX12		MUX1 select bit 2	W	0	H2, H3
21	MUX20		MUX2 select bit 0	W	0	H4, H5
22	MUX21	MUX2	MUX2 select bit 1	W	1	H4, H5
23	MUX22		MUX2 select bit 2	W	0	H4, H5
24	MUX30		MUX3 select bit 0	W	1	H6, H7
25	MUX31	MUX3	MUX3 select bit 1	W	1	H6, H7
26	MUX32		MUX3 select bit 2	W	0	H6, H7
27	MUX40		MUX4 select bit 0	W	1	G8, F8
28	MUX41	MUX4	MUX4 select bit 1	W	1	G8, F8
29	MUX42		MUX4 select bit 2	W	0	G8, F8
30	CP_DIR		Determines in which direction CP should regulate, if REF_CLK is faster than VCXO_CLK, and vice versa (see Figure 2)	W	1	A4
31	REXT		Enable external reference resistor (1 = enabled)	W	0	C1

Table 2. Word 1

<sup>†</sup> The frequency applied to the Divider N must be smaller than 250 MHz. A sufficient P Divider must be selected with the MUX\_SEL to maintain this criteria.



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BIT	T BIT NAME		DESCRIPTION / FUNCTION	TYPE	POWER-UP CONDITION	PIN AFFECTED
0	C0		Register selection	W	0	
1	C1		Register selection	W	1	
2	HOLD		Enables the hold functionality (1 = enabled)	W	0	A4
3	NPD		PD current sources, resets the dividers and 3-states all outputs (0 = active)	W	1	
4	NRESET		RESET all dividers (0 = active)	W	1	
5	ENBG		Enable bandgap (1 = enabled), see Note 2	W	1	C1
6	LOCKW 0		Lock detect window bit 0	W	0	A8
7	LOCKW 1		Lock detect window bit 1	W	0	A8
8	RES		Reserved	W	Х	
9	RES		Reserved	W	Х	
10	RES		Reserved	W	Х	
11	RES		Reserved	W	Х	
12	RES		Reserved	W	Х	
13	RES		Reserved	W	Х	
14	RES		Reserved	W	Х	
15	RES		Reserved	W	Х	
16	RES		Reserved	W	Х	
17	RES		Reserved	W	Х	
18	RES		Reserved	W	Х	
19	RES		Reserved	W	Х	
20	RES		Reserved	W	Х	
21	RES		Reserved	W	Х	
22	RES		Reserved	W	Х	
23	RES		Reserved	W	Х	
24	RES		Reserved	W	Х	
25	RES		Reserved	W	Х	
26	RES		Reserved	W	Х	
27	RES		Reserved	W	Х	
28	RES		Reserved	W	Х	
29	RES		Reserved	W	Х	
30	RES		Reserved	W	Х	
31	RES		Reserved	W	Х	

#### Table 3. Word 2

NOTE 2: The reference voltage for the charge pump and LVPECL output circuitry can be generated in two ways. One way is to enable ENBG and the other way is to use the voltage divider circuitry (internal or external). It is recommended to enable ENBG because it gives an accurate value and it is independent on temperature variation.



BIT	BIT NAME	DESCRIPTION / FUNCTION	TYPE	POWER-UP CONDITION	PIN AFFECTED
0	C0	Register selection	W	1	
1	C1	Register selection	W	1	
2	RES	Reserved	W	0	
3	RES	Reserved	W	0	
4	RES	Reserved	W	0	
5	RES	Reserved	W	0	
6	RES	Reserved	W	0	
7	RES	Reserved	W	0	
8	RES	Reserved	W	0	
9	RES	Reserved	W	0	
10	RES	Reserved	W	0	
11	RES	Reserved	W	0	
12	RES	Reserved	W	0	
13	RES	Reserved	W	0	
14	RES	Reserved	W	0	
15	RES	Reserved	W	0	
16	RES	Reserved	W	0	
17	RES	Reserved	W	0	
18	RES	Reserved	W	0	
19	RES	Reserved	W	0	
20	RES	Reserved	W	0	
21	RES	Reserved	W	0	
22	RES	Reserved	W	0	
23	RES	Reserved	W	0	
24	RES	Reserved	W	0	
25	RES	Reserved	W	0	
26	RES	Reserved	W	0	
27	RES	Reserved	W	0	
28	RES	Reserved	W	0	
29	RES	Reserved	W	0	
30	RES	Reserved	W	0	
31	RES	Reserved	W	0	

#### Table 4. Word 3 (See Note 3)

NOTE 3: It is recommended to program all register bits of Word 3 to 0 along with other Registers.



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### functional description of the logic

M9	M8	M7	M6	M5	M4	M3	M2	M1	MO	DIV BY <sup>†</sup>	DEFAULT
0	0	0	0	0	0	0	0	0	0	1	
0	0	0	0	0	0	0	0	0	1	2	
0	0	0	0	0	0	0	0	1	0	3	
0	0	0	0	0	0	0	0	1	1	4	
					•						
0	0	0	1	1	1	1	1	1	1	128	Yes
					• •						
1	1	1	1	1	1	1	1	0	1	1022	
1	1	1	1	1	1	1	1	1	0	1023	
1	1	1	1	1	1	1	1	1	1	1024	

#### Table 5. Reference Divider M and VCXO Divider N (See Note 4)

NOTE 4: If the divider value is Q, then the code will be the binary value of (Q-1).

<sup>†</sup> The frequency applied to the Divider N must be smaller than 250 MHz. A sufficient P Divider must be selected with the MUX\_SEL to maintain this criteria.

#### Table 6. Reference Delay M and VCXO Delay N

MD2/ND2	MD1/ND1	MD0/ND0	DELAY <sup>†</sup>	DEFAULT
0	0	0	0 ps	Yes
0	0	1	150 ps	
0	1	0	300 ps	
0	1	1	450 ps	
1	0	0	600 ps	
1	0	1	750 ps	
1	1	0	1.5 ns	
1	1	1	2.75 ns	

<sup>†</sup> Typical values at V<sub>CC</sub> = 3.3 V, temperature =  $25^{\circ}$ C

#### Table 7. PFD Pulse Width Delay

PFD2	PFD1	PFD0	ADDITIONAL PULSE WIDTH <sup>†</sup>	DEFAULT
0	0	0	0 ps	Yes
0	0	1	300 ps	
0	1	0	600 ps	
0	1	1	900 ps	
1	0	0	1.5 ns	
1	0	1	2.1 ns	
1	1	0	2.7 ns	
1	1	1	3.7 ns	

<sup>†</sup>Typical values at  $V_{CC}$  = 3.3 V, temperature = 25°C



## functional description of the logic (continued)

#### **Table 8. Lock Detect Window**

LockW 1	LockW 0	REF_IN TO Yn TOLERABLE PHASE OFFSET (See Figure 4 and Note 1)	DEFAULT
0	0	±1.2 ns	Yes
0	1	±1.8 ns	
1	0	±2.4 ns	
1	1	±3 ns	

NOTE 1: Determined at PFD – REF\_IN and Yn feed through M/N Divider and M/N Delay.

# **Table 9. Charge Pump Current**

CP3	CP2	CP1	CP0	NOMINAL CHARGE PUMP CURRENT <sup>†</sup>	DEFAULT
0	0	0	0	0.625 mA	
0	0	0	1	1.25 mA	
0	0	1	0	1.875 mA	
0	0	1	1	2.5 mA	
0	1	0	0	3.125 mA	
0	1	0	1	3.75 mA	
0	1	1	0	4.375 mA	
0	1	1	1	5 mA	
1	0	0	0	1 mA	
1	0	0	1	2 mA	Yes
1	0	1	0	3 mA	
1	0	1	1	4 mA	
1	1	0	0	5 mA	
1	1	0	1	6 mA	
1	1	1	0	7 mA	
1	1	1	1	8 mA	

 $\dagger$  With an internal or external reference resistor (12 k $\Omega$ ) in use.

#### **Table 10. MUXSEL Selection**

MUXS2	MUXS1	MUXS0	SELECTED VCXO SIGNAL FOR THE PHASE DISCRIMINATOR	DEFAULT
0	0	0	Y0	
0	0	1	Y1	
0	1	0	Y2	
0	1	1	Y3	Yes
1	0	0	Y4	
1	0	1	Y3	
1	1	0	Y3	
1	1	1	Y3	



## functional description of the logic (continued)

MUX2	MUX1	MUX0	SELECTED DIVIDED VCXO SIGNAL	DEFAULT
0	0	0	Div by 1	For Y0
0	0	1	Div by 2	For Y1
0	1	0	Div by 4	For Y2
0	1	1	Div by 8	For Y3 and Y4
1	0	0	Div by 16	
1	0	1	Div by 8	
1	1	0	Div by 8	
1	1	1	Div by 8	

#### Table 11. MUX0, MUX1, MUX2, MUX3, and MUX4 Selection



#### Figure 2. Charge Pump Current Direction



#### functional description of the logic (continued)



NOTES: A. For a proper hold functionality the following conditions must be maintained:

- Counter M and counter N need to have the same divider ratio
- fref\_in max = 75 MHz
- Duty cycle of 45% to 55% for 25 MHz <= fref\_in < 50 MHz
- Duty cycle of 40% to 60% for 50 MHz <= fref\_in < 75 MHz
- Duty cycle of fVCXO should be in 50% range

The hold functionality is triggered by the first missing REF\_IN cycle. It is disabled in default mode (bit 2 of word 2 = 0). While the device is in frequency hold mode, a possible leakage current caused by the external filter and VCXO may change the VCXO control voltage, and therefore changing the VCXO frequency. To keep the frequency drift as low as possible, a low leakage current filter design is recommended or the number of the disrupted / missing REF\_IN clock cycles should be kept low (< 100).

#### **Figure 3. State Machine Operation**



NOTE: If the rising edge of REF\_IN clock and VCXO\_IN clock for PFD are inside the lock detect window (t(lockdetect)) for at least five successive input clock periods, then the PLL is considered to be locked. In this case, the STATUS\_LOCK output is set to high level. The size of the lock detect window is programmable via the SPI control logic (bit 6 and 7 of word 2). (See Table 8)





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#### absolute maximum ratings over operating free-air temperature (unless otherwise noted)<sup>†</sup>

Supply voltage range, V <sub>CC</sub> , AV <sub>CC</sub> (see Note 2)	
Input voltage range, V <sub>I</sub> (see Note 3)	$-0.5$ V to V <sub>CC</sub> + 0.5 V
Output voltage range, V <sub>O</sub> (see Note 3)	$-0.5$ V to V <sub>CC</sub> + 0.5 V
Input current ( $V_1 < 0, V_1 > V_{CC}$ )	±20 mA
Output current for LVPECL outputs ( $0 < V_O < V_{CC}$ )	–50 mA
Continuous output current, I <sub>O</sub>	±50 mA
Storage temperature range T <sub>stg</sub>	–65°C to 150°C
Maximum junction temperature, TJ	

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 2. All supply voltages must be the same value and must be supplied at the same time.

NOTES: 3. The input and output negative voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

#### package thermal resistance for RGZ (QFN) package (see Note 4 and Note 5)

AIRFLOW (LFM)	θ <sub>JA</sub> (°C/W)	θ <b>JC (°C/W)</b>	θ <sub>JP</sub> (°C/W)	Ψ <b>J</b> T (°C/W)
0	29.9	22.4	1.5	0.2
15	24.7			0.2
250	23.2			0.2
500	21.5			0.3

NOTE 4: The package thermal impedance is calculated in accordance with JESD 51 and JEDEC2S2P (high-k board). NOTE 5: Connected to GND with nine thermal vias (0,3 mm diameter).

#### package thermal resistance for ZVA (BGA) package (see Note 6)

AIRFLOW (m/s)	θ <sub>JA</sub> (°C/W)	θ <sub>JC</sub> (°C/W)	θ <sub>JB</sub> (°C/W)	Ψ <b>JT (°C/W)</b>
0	54	29.9	44.5	0.9
1	49			0.9
2.5	47.2			0.9

NOTE 6: The package thermal impedance is calculated in accordance with JESD 51 and JEDEC2S2P (high-k board).

#### recommended operating conditions

	MIN	NOM	MAX	UNIT
Supply voltage, V <sub>CC</sub>	3	3.3	3.6	V
Operating free-air temperature, T <sub>A</sub>	-40		85	°C
Low-level input voltage LVCMOS, VIL			0.3 V <sub>CC</sub>	V
High-level input voltage LVCMOS, VIH	0.7 V <sub>CC</sub>			V
Input threshold voltage LVCMOS, VIT		0.5 V <sub>CC</sub>		V
High-level output current LVCMOS, IOH			-6	mA
Low-level output current LVCMOS, IOL			6	mA
Input voltage range LVCMOS, VI	0		3.6	V
Input amplitude LVPECL, VINPP [(VVCXO_IN - VVCXO_INB), See Note 7]	0.5		1.3	V
Common-mode input voltage LVPECL, VIC	V <sub>CC</sub> -2		V <sub>CC</sub> -0.4	V

NOTE 7: VINPP minimum and maximum is required to maintain ac specifications; the actual device function tolerates at a minimum VINPP of 100 mV.



timing requirements over recommended ranges of supply voltage, load, and operating free-air temperature

	PARAMETER	MIN	TYP	MAX	UNIT
REF_IN Requ	irements	-			
fREF_IN	LVCMOS reference clock frequency	3.5		180	MHz
t <sub>r</sub> / t <sub>f</sub>	Rise and fall time of REF_IN signal from 20% to 80% of $V_{\mbox{CC}}$			4	ns
dutyREF	Duty cycle of REF_IN at V <sub>CC</sub> / 2	40%		60%	
VCXO_IN, VC	XO_INB Requirements				
<sup>f</sup> VCXO_IN	LVPECL VCXO clock frequency	10		800	MHz
t <sub>r</sub> / t <sub>f</sub>	Rise and fall time 20% to 80% of V $_{\mbox{\scriptsize INPP}}$ at 80 MHz to 800 MHz (see Note 8)			3	ns
dutyVCXO	Duty cycle of VCXO clock	40%		60%	
SPI/Control F	Requirements (See Figure 1)	-			
fCTRL_CLK	CTRL_CLK frequency			20	MHz
<sup>t</sup> su1	CTRL_DATA to CTRL_CLK setup time	10			ns
t <sub>h2</sub>	CTRL_DATA to CTRL_CLK hold time	10			ns
tg	CTRL_CLK high duration	25			ns
t <sub>4</sub>	CTRL_CLK low duration	25			ns
t <sub>su5</sub>	CTRL_LE to CTRL_CLK setup time	10			ns
<sup>t</sup> su6	CTRL_CLK to CTRL_LE setup time	10			ns
t7	CTRL_LE pulse width	20			ns
t <sub>r</sub> / t <sub>f</sub>	Rise and fall time of CTRL_DATA CTRL_CLK, CTRL_LE from 20% to 80% of $V_{CC}$			5	ns
NPD / NRESE	T Requirements				
t <sub>r</sub> / t <sub>f</sub>	Rise and fall time of the NRESET, NPD signal from 20% to 80% of V $_{ m CC}$			4	ns

NOTES: 8. Use a square wave for lower frequencies (< 80 MHz).



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# device characteristics over recommended operating free-air temperature range (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP <sup>†</sup>	MAX	UNIT
Overall					ı	
ICC	Supply current (see Note 9)	$f_{VCXO} = 245 \text{ MHz}, f_{REF_IN} = 30 \text{ MHz},$ $V_{CC} = 3.6 \text{ V}, \text{ AV}_{CC} = 3.6 \text{ V},$ $f_{PFD} = 240 \text{ kHz}, I_{CP} = 2 \text{ mA},$ (see Note 11 and Note 13)		230	265	mA
ICCPD	Power-down current	$f_{IN} = 0 \text{ MHz}, V_{CC} = 3.6 \text{ V},$ AV <sub>CC</sub> = 3.6 V, V <sub>I</sub> = 0 V or V <sub>CC</sub>		100	300	μΑ
<sup>t</sup> pho	Phase offset (REF_IN to Y output) (see Note 10)	VREF_IN = VCC/2, Crossing point of Y, See Figure 12	-150		150	ps
LVCMOS		÷	•			
VIK	LVCMOS input voltage	$V_{CC} = 3 V, I_{I} = -18 mA$			-1.2	V
lj	LVCMOS input current	$V_I = 0 V \text{ or } V_{CC}, V_{CC} = 3.6 V$			±5	μA
Ι <sub>Η</sub>	LVCMOS input current for NPD, NRESET	VI = V <sub>CC</sub> , V <sub>CC</sub> = 3.6 V			5	μΑ
IIL	LVCMOS input current for NPD, NRESET	V <sub>I</sub> = 0 V, V <sub>CC</sub> = 3.6 V	-15		-35	μΑ
VOH	LVCMOS high-level output voltage	I <sub>OH</sub> = -12 mA, V <sub>CC</sub> = 3 V	2.1			V
V <sub>OL</sub>	LVCMOS low-level output voltage	I <sub>OL</sub> = 12 mA, V <sub>CC</sub> = 3 V			0.55	V
Cl	Input capacitance at REF_IN	$V_I = 0 V \text{ or } V_{CC}$		2		pF
Cl	Input capacitance at CTRL_LE, CTRL_CLOCK, CTRL_DATA	VI = 0 V  or  VCC		2		pF
<sup>t</sup> detectREF	Frequency detect time until STATUS_REF is valid	fREF_IN = 3.5 MHz		5		μs
<sup>t</sup> detectVCXO	Frequency detect time until STATUS_VCXO is valid	f <sub>VCXO_IN</sub> = 10 MHz		5		μs
LVPECL			•		<b>·</b>	
l	LVPECL input current	$V_{I} = 0 V \text{ or } V_{CC}$			±100	μΑ
IOZ	LVPECL output current 3-state	$V_{O} = 0 V \text{ or } V_{CC} - 0.8 V$			20	μΑ
VOH	LVPECL high-level output voltage	See Note 11	V <sub>CC</sub> -1.18		V <sub>CC</sub> -0.81	V
V <sub>OL</sub>	LVPECL low-level output voltage	See Note 11	V <sub>CC</sub> -1.98		V <sub>CC</sub> -1.55	V
Vod	Differential output voltage	$10 \le f_{OUT} \le 800 \text{ MHz}$ , See Figure 6	500			mV

 $\dagger$  All typical values are at V\_CC = 3.3 V, temperature = 25°C.

NOTES: 9. For I<sub>CC</sub> over frequency see Figure 5.

10. This is valid only for same REF\_IN clock and Y output clock frequency. It can be adjusted by the SPI controller (reference delay M and VCXO delay N).

11. Outputs are terminated through a 50- $\Omega$  resistor to V<sub>CC</sub> – 2 V.

12. The  $t_{sk(0)}$  specification is only valid for equal loading of all outputs.

13. All output switching at default divider ratios.



#### device characteristics over recommended operating free-air temperature range (unless otherwise noted)(continued)

	PARAMETER	TEST CONDITIONS	MIN	TYP†	MAX	UNIT
<sup>t</sup> PLH <sup>/t</sup> PHL	Propagation delay rising/falling edge	VCXO_IN to Yn	500		950	ps
tsk(p)	LVPECL pulse skew				15	ps
<b>4</b>		See Figure 11, Mode 1–2–4–8–8			60	ps
<sup>t</sup> sk(o)	LVPECL output skew (see Note 14)	See Figure 11, Mode 1–1–1–1–1			30	ps
t <sub>r</sub> / t <sub>f</sub>	Rise and fall time	20% to 80% of $V_{OD}$ , See Figure 10	180		350	ps
Cl	Input capacitance at VCXO_IN, VCXO_IB			1.5		pF
Phase Dete	ctor	·				-
fCPmax	Maximum charge pump frequency	PFD pulse width delay is 0 ps		100		MHz
Charge Pur	np					
ICP	Charge pump sink/source current range	$V_{CP} = 0.5 V_{CC}$ , See Table 9	±0.625		±8	mA
I <sub>CP3St</sub>	Charge pump 3-state current	$0.5 V < V_{CP} < V_{CC} - 0.5 V$		1	30	nA
ICPA	ICP absolute accuracy	$V_{CP} = 0.5 V_{CC}$			20%	
ICPM	Sink/source current matching	V <sub>CP</sub> = 0.5 V <sub>CC</sub>		5%		
IVCPM	ICP vs VCP matching	0.5 V < V <sub>CP</sub> < V <sub>CC</sub> - 0.5 V		10%		
Operational		<u> </u>				
IS	Supply current	$AV_{CC} = 3.6 V$		2	5	mA
VIO	Input offset voltage			2		mV
I <sub>IB</sub>	Input bias current	(  I <sub>OPA_IP</sub>   +   I <sub>OPA_IN</sub>  ) / 2		1	30	nA
IIO	Input offset current			1	10	nA
RI	Input resistance	0.5 V <sub>CC</sub> ±500 mV	10			MΩ
VICR	Common-mode input voltage range		0.2		V <sub>CC</sub> -0.2	V
AOL	Open-loop voltage gain	See Figure 17, f = 1 kHz		70		dB
GBW	Gain bandwidth	See Figure 14		3		MHz
SR	Slew rate	See Figure 14, 20% – 80% of VO		1		V/µs
		R <sub>L</sub> = 10 kΩ	0.2		V <sub>CC</sub> -0.2	
VO	Output voltage swing	$R_L = 2 k\Omega$	0.3		V <sub>CC</sub> -0.3	V
RO	Output resistance			60		Ω
		Sourcing		-20		
IOS	Short-circuit output current	Sinking		50		mA
CMRR	Common-mode rejection ratio	V <sub>INPP</sub> = 500 mV and f = 1 kHz, (see Figure 15)		80		dB
PSRR	Power supply rejection ratio	AVCC modulated with sine wave from 3 V to 3.6 V and f = 100 Hz (see Figure 16)		60		dB
Vn	Input noise voltage	$f = 1 \text{ kHz}$ , see Figure 14, $V_{IN} = 0 \text{ V}$		500		nV/√I

<sup>†</sup> All typical values are at V<sub>CC</sub> = 3.3 V, temperature =  $25^{\circ}$ C.

NOTE 14: The  $t_{sk(0)}$  specification is only valid for equal loading of all outputs.





NOTE A: P<sub>DEV</sub> = P<sub>Tot</sub> - P<sub>Term</sub> P<sub>DEV</sub> = Device power consumption, P<sub>Tot</sub> = Total power consumption, P<sub>Term</sub> = Termination power consumption

Figure 5. I<sub>CC</sub> / P<sub>DEV</sub> vs Frequency



Figure 6. Differential Output Swing (V<sub>OD</sub>) vs Frequency



## **APPLICATION INFORMATION**

### Phase Noise Reference Circuit (See the EVM)



Figure 7. Typical Applications Diagram With Passive Loop Filter



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# **CDC7005 3.3-V HIGH PERFORMANCE CLOCK SYNTHESIZER AND JITTER CLEANER**

#### SCAS685L-DECEMBER 2002 - REVISED JUNE 2009

#### application specific device characteristics over recommended operating free-air temperature range (unless otherwise noted)

	PARAMETER	REF_IN PHASE	VCXO PHASE	Yn PHASE NOISE AT 30.72 MHz	UNIT
		NOISE AT 30.72 MHz	NOISE AT 245.76 MHz	ΜΙΝ ΤΥΡ <sup>†</sup> ΜΑΧ	
phn <sub>10</sub>	Phase noise at 10 Hz	-115	-77	-105	dBc/Hz
phn <sub>100</sub>	Phase noise at 100 Hz	-125	-95	-116	dBc/Hz
phn <sub>1k</sub>	Phase noise at 1 kHz	-131	-118	-135	dBc/Hz
phn <sub>10k</sub>	Phase noise at 10 kHz	-136	-136	-147	dBc/Hz
phn <sub>100k</sub>	Phase noise at 100 kHz	-138	-138	-152	dBc/Hz
phn <sub>240k</sub>	Phase noise at 240 kHz	-140	-143	-152	dBc/Hz
<sup>t</sup> stabi	PLL stabilization time, (see Note 15)			200	ms

<sup>†</sup>Output phase noise is dependent on the noise of the REF\_IN clock and VCXO clock noise floor.

NOTES: 15. The typical stabilization time is based on the above application example at a loop bandwidth of 20 Hz.

16. For further explanations as well as phase noise/jitter test results using various VCXOs, see application note SCAA067.



## **APPLICATION INFORMATION**

#### information on the clock generation for interpolating DACs with the CDC7005

The CDC7005, with its specified phase noise performance, is an ideal sampling clock generator for high speed ADCs and DACs. The CDC7005 is especially of interest for the new high speed DACs, which have integrated interpolation filter. Such DACs achieve sampling rates up to 500 MSPS. This high data rate can typically not be supported from the digital side driving the DAC (e.g., DUC, digital up-converter). Therefore, one approach to interface the DUC to the DAC is the integration of an interpolation filter within the DAC to reduce the data rate at the digital input of the DAC. In 3G systems, for example, a common sampling rate of a high speed DAC is 245.76 MSPS. With a four times interpolation of the digital data, the required input data rate results into 61.44 MSPS, which can be supported easily from the digital side. The DUC GC4116, which supports up to two WCDMA carriers, provides a maximum output data rate of 100 MSPS. An example is shown in Figure 8, where the CDC7005 supplies the clock signal for the DUC/DDC and ADC/DAC.



Figure 8. CDC7005 as a Clock Generator for High Speed ADCs and DACs

The generation of the two required clock signals (data input clock, clock for DAC) for such an interpolating DAC can be done in different ways. The easiest way would be to provide an internal PLL multiplier, which is capable of generating the fast sampling clock for the DAC from the data input clock signal. However, the process of the DAC is usually not optimized for best phase noise performance, while the CDC7005 is optimized exactly for this. The CDC7005 therefore provides the preferred clocking scheme for the DAC5686. The DAC5686 demands that the edges of the two input clocks must be phase aligned within  $\pm$ 500 ps for latching the data properly. This phase alignment is well achieved with the CDC7005, which assures a maximum skew of 200 ps of the different different outputs to each other.



## **APPLICATION INFORMATION**

Another advantage of this clock solution is that the ADC or DAC can be driven directly in an ac-coupling interface as shown in Figure 9, with an external termination in a differential configuration. There is no need for a transformer to generate a differential signal from a single-ended clock source.



Figure 9. Driving DAC or ADC with PECL Output of the CDC7005







Figure 10. LVPECL Differential Output Voltage and Rise/Fall Time



Figure 11. Output Skew





## PARAMETER MEASUREMENT INFORMATION

Figure 12. Phase Offset



Figure 13. Typical Termination for Output Driver





#### PARAMETER MEASUREMENT INFORMATION





NOTE: CMRR (dB) = 20 x Log ( $V_{IN}/(V_{IN} - V_{OUT})$ ) x (1 + 900/180)

Figure 15. CMRR Test Circuits



Figure 16. PSRR Test Circuit



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## PARAMETER MEASUREMENT INFORMATION





## **PACKAGING INFORMATION**

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead finish/ Ball material	MSL Peak Temp (3)	Op Temp (°C)	Device Marking (4/5)	Samples
							(6)				
CDC7005RGZT	ACTIVE	VQFN	RGZ	48	250	RoHS & Green	NIPDAU	Level-3-260C-168 HR	-40 to 85	CDC7005	Samples
CDC7005ZVA	ACTIVE	BGA	ZVA	64	348	RoHS & Non-Green	SNAGCU	Level-3-260C-168 HR	-40 to 85	CK7005Z	Samples
CDC7005ZVAR	ACTIVE	BGA	ZVA	64	1000	RoHS & Non-Green	SNAGCU	Level-3-260C-168 HR	-40 to 85	CK7005Z	Samples
CDC7005ZVAT	ACTIVE	BGA	ZVA	64	250	RoHS & Non-Green	SNAGCU	Level-3-260C-168 HR	-40 to 85	CK7005Z	Samples

<sup>(1)</sup> The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

**LIFEBUY:** TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

**PREVIEW**: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

<sup>(2)</sup> RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

**RoHS Exempt:** TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <= 1000ppm threshold. Antimony trioxide based flame retardants must also meet the <= 1000ppm threshold requirement.

<sup>(3)</sup> MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

<sup>(4)</sup> There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

<sup>(6)</sup> Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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10-Dec-2020

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Addendum-Page 2

# PACKAGE MATERIALS INFORMATION

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# TAPE AND REEL INFORMATION





## QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal												
Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
CDC7005RGZT	VQFN	RGZ	48	250	180.0	16.4	7.3	7.3	1.5	12.0	16.0	Q2
CDC7005ZVAR	BGA	ZVA	64	1000	330.0	16.4	8.3	8.3	2.25	12.0	16.0	Q1
CDC7005ZVAT	BGA	ZVA	64	250	180.0	16.4	8.3	8.3	2.25	12.0	16.0	Q1

TEXAS INSTRUMENTS

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# PACKAGE MATERIALS INFORMATION

12-Feb-2019



\*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
CDC7005RGZT	VQFN	RGZ	48	250	213.0	191.0	55.0
CDC7005ZVAR	BGA	ZVA	64	1000	350.0	350.0	43.0
CDC7005ZVAT	BGA	ZVA	64	250	213.0	191.0	55.0

# **RGZ 48**

7 x 7, 0.5 mm pitch

# **GENERIC PACKAGE VIEW**

# VQFN - 1 mm max height

PLASTIC QUADFLAT PACK- NO LEAD



Images above are just a representation of the package family, actual package may vary. Refer to the product data sheet for package details.



# **RGZ0048B**



# **PACKAGE OUTLINE**

## VQFN - 1 mm max height

PLASTIC QUAD FLATPACK - NO LEAD



#### NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M. 2. This drawing is subject to change without notice.
- 3. The package thermal pad must be soldered to the printed circuit board for thermal and mechanical performance.



# **RGZ0048B**

# **EXAMPLE BOARD LAYOUT**

# VQFN - 1 mm max height

PLASTIC QUAD FLATPACK - NO LEAD



NOTES: (continued)

 This package is designed to be soldered to a thermal pad on the board. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/slua271).

 Vias are optional depending on application, refer to device data sheet. If any vias are implemented, refer to their locations shown on this view. It is recommended that vias under paste be filled, plugged or tented.



# **RGZ0048B**

# **EXAMPLE STENCIL DESIGN**

# VQFN - 1 mm max height

PLASTIC QUAD FLATPACK - NO LEAD



Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.



ZVA (S-PBGA-N64)

PLASTIC BALL GRID ARRAY



- B. This drawing is subject to change without notice.
- C. This is a Pb-free package.



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